Features

- CRM(CQ) Super_Junction technology
- Much lower Ron*A performance for On-state efficiency
- Better efficiency due to very low FOM
- Ultra-fast body diode
- Qualified for industrial grade applications according to JEDEC

Product Summary

$V_{DS,min}$	600V
$R_{DS(on),typ}$	32mΩ
I_D	58A

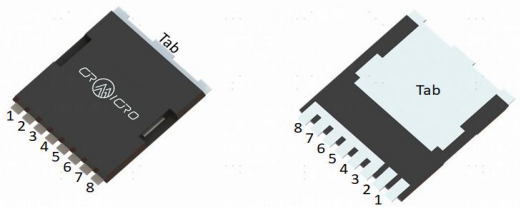
Applications

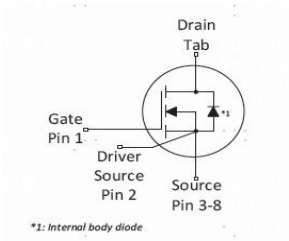
- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS -Micro Inverter System
- Charger
- Power Supply

100% DVDS Tested
100% Avalanche Tested

RoHS HF

Top view Bottom view





Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJZ35N60G4FZ	CRJZ35N60G4FZ	TOLL	Tape&Reel	N/A	N/A	2000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	600	V
Continuous drain current [1)] T_C = 25℃ T_C = 100℃	I_D	 58 37	A
Pulsed drain current [2)] (T_C = 25℃, t_p limited by $T_{j,max}$)	$I_{D,pulse}$	173	A
Avalanche energy, single pulse (L=30mH)	E_{AS}	540	mJ
MOSFET dv/dt ruggedness	dv/dt	120	V/ns
Gate-Source voltage	V_{GS}	±30	V
Power dissipation (T_C = 25℃)	P_{tot}	270	W
Continuous diode forward current(T_C = 25℃)	I_S	58	A
Diode pulse current [2)] (T_C = 25℃)	$I_{S,pulse}$	173	A
Recovery diode dv/dt [3)]	dv/dt	70	V/ns
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	℃

1) Limited by $T_{j,max}$. Maximum Duty Cycle D = 0.50
2) Pulse width t_p limited by $T_{j,max}$
3) Identical low side and high side switch with identical R_g

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case	R_{thJC}	-	0.33	0.46	℃/W	
Thermal resistance, junction – ambient	R_{thJA}	-	-	50	℃/W	

Electrical Characteristic (at T_j = 25℃, unless otherwise specified)

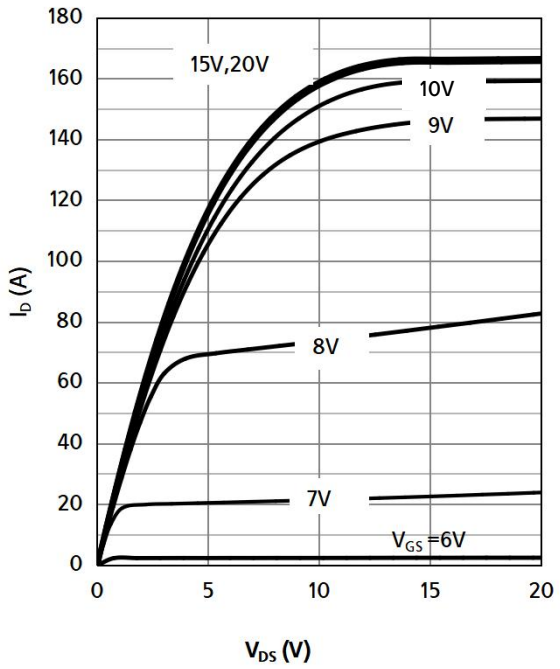
Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	600	-	-	V	V_{GS}=0V,I_D=1mA
Gate threshold voltage	$V_{GS(th)}$	3	-	5	V	V_{DS}=V_{GS},I_D=2mA
Zero gate voltage drain current	I_{DSS}	- -	- 1000	10 -	μA	V_{DS}=600V,V_{GS}=0V T_j=25℃ T_j=150℃
Gate-source leakage current	I_{GSS}	-	-	±100	nA	V_{GS}=±30V,V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	- -	32 71	38 -	mΩ	V_{GS}=10V,I_D=25A, T_j=25℃ T_j=150℃
Transconductance	g_{fs}	-	45	-	S	V_{DS}=20V,I_D=25A
Dynamic Characteristic						
Input Capacitance	C_{iss}	-	4640	-	pF	V_{GS}=0V, V_{DS}=100V, f=100KHz
Output Capacitance	C_{oss}	-	135	-		
Reverse Transfer Capacitance	C_{rss}	-	3	-		
Gate Total Charge	Q_g	-	110	-	nC	V_{GS}=10V, V_{DS}=480V, I_D=25A
Gate-Source charge	Q_{gs}	-	35	-		
Gate-Drain charge	Q_{gd}	-	40	-		
Gate plateau voltage	$V_{plateau}$	-	6	-	V	
Turn-on delay time	$t_{d(on)}$	-	30	-	ns	V_{GS}=10V, I_D=25A, V_{DS}=400V, R_g=3Ω
Rise time	t_r	-	30	-		
Turn-off delay time	$t_{d(off)}$	-	75	-		
Fall time	t_f	-	20	-		
Gate resistance	$R_{g,int}$	-	2.0	-	Ω	f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.7	0.9	1.1	V	V_{GS}=0V,I_{SD}=25A
Body Diode Reverse Recovery Time	t_{rr}	-	120	-	ns	I_{SD}=25A di_F/dt=100A/μs V_{DS}=400V
Body Diode Reverse Recovery Charge	Q_{rr}	-	0.6	-	μC	
Body Diode Reverse Recovery Peak Current	I_{rrm}	-	8.5	-	A	

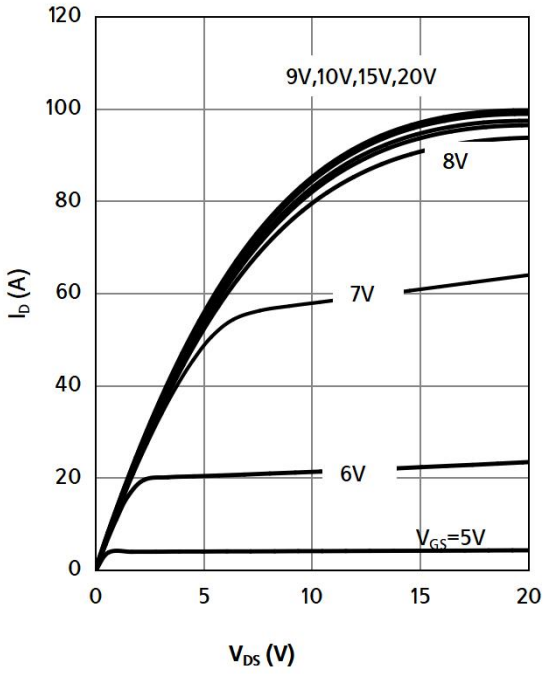
Typical Performance Characteristics

Fig 1. Output Characteristics (T_j=25℃)



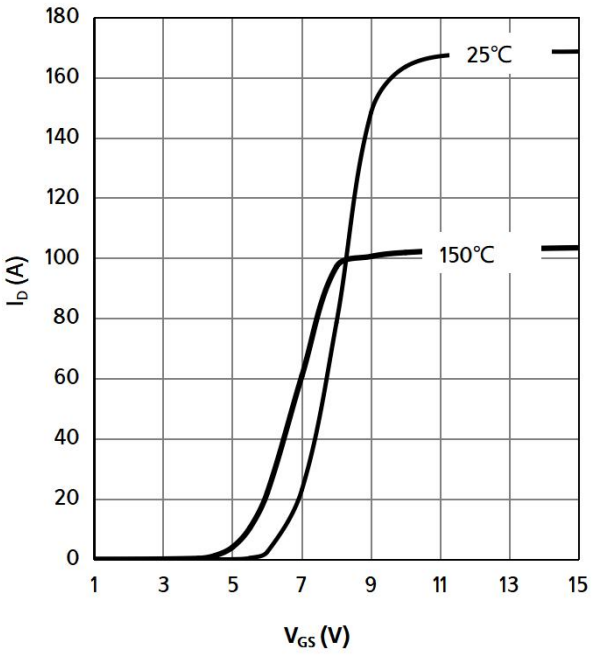
I_D=f(V_{DS});T_j=25℃;parameter: V_{GS}

Fig 2. Output Characteristics (T_j=150℃)



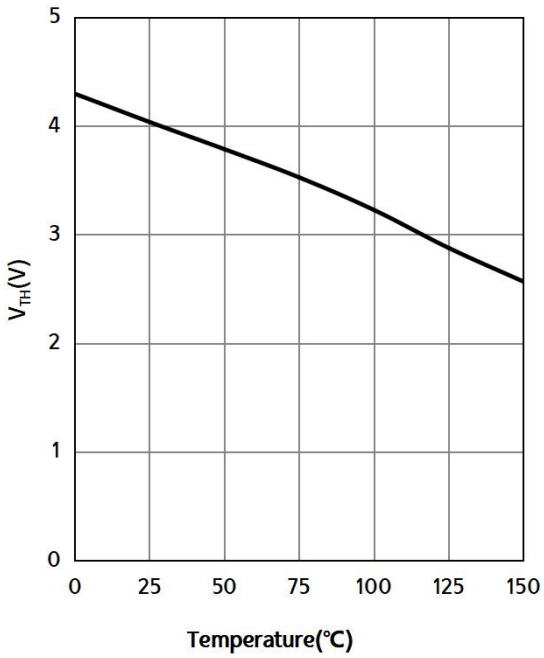
I_D=f(V_{DS});T_j=150℃;parameter: V_{GS}

Fig 3: Transfer Characteristics



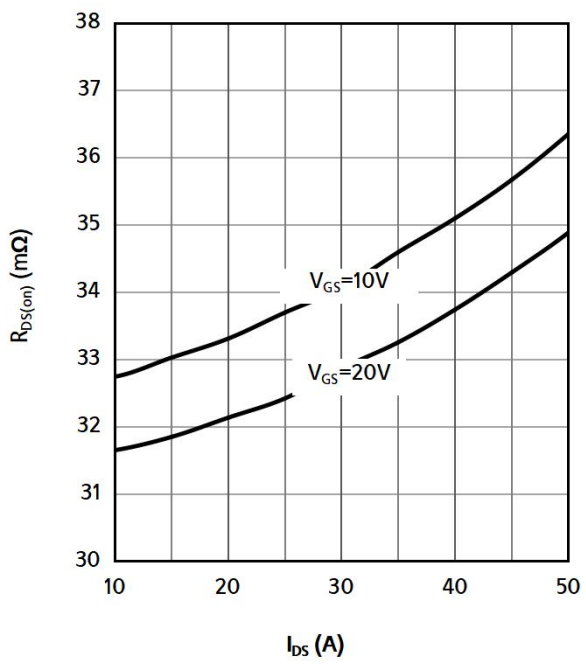
I_D=f(V_{GS});V_{DS}=20V;parameter: T_j

Fig 4: V_{TH} vs. T_j Temperature Characteristics



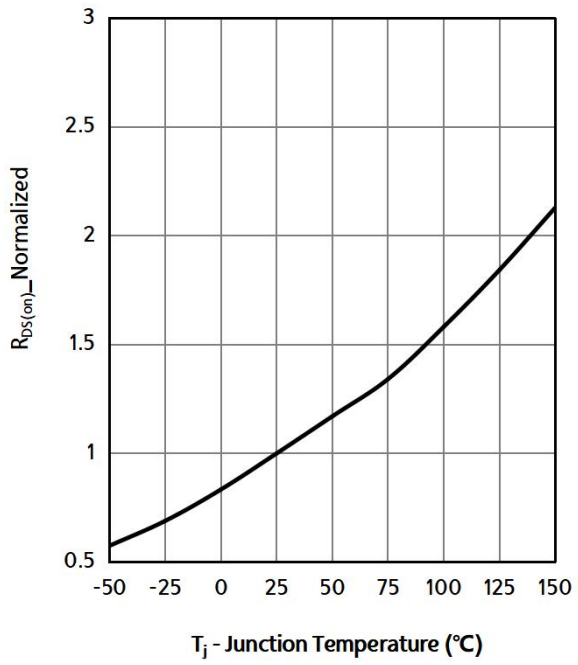
V_{TH}=f(T_j);I_D=2mA

Fig 5: $R_{DS(on)}$ vs. I_{DS} Characteristics(T_j=25℃)



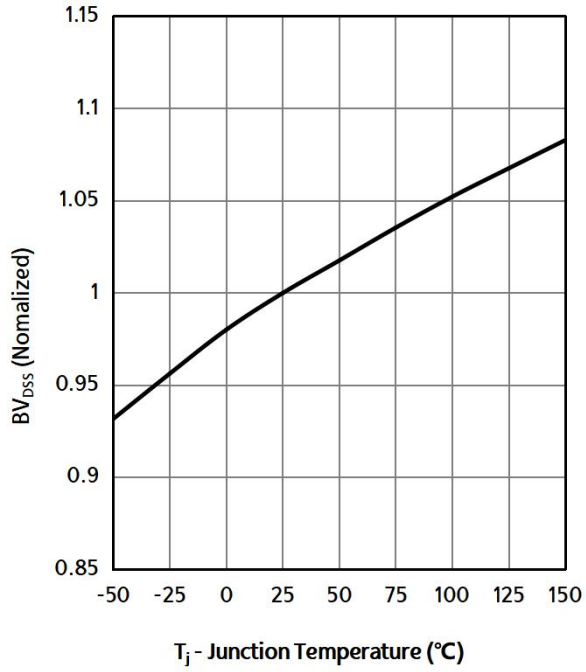
$R_{DS(on)}$=f(I_D);T_j=25℃;parameter: V_{GS}

Fig 6: $R_{DS(on)}$ vs. Temperature



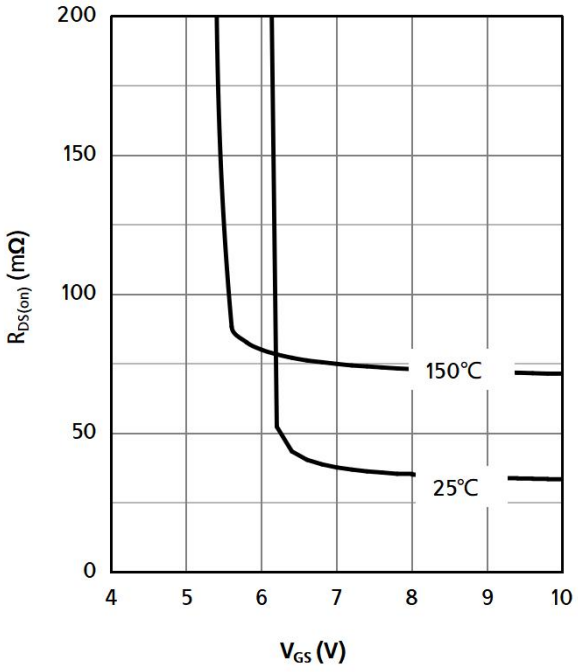
$R_{DS(on)}$=f(T_j);I_D=25A;V_{GS}=10V

Fig 7: BV_{DSS} vs. Temperature



BV_{DSS}=f(T_j)

Fig 8: $R_{DS(on)}$ vs. Gate Voltage



$R_{DS(on)}$=f(V_{GS});I_D=25A;parameter: T_j

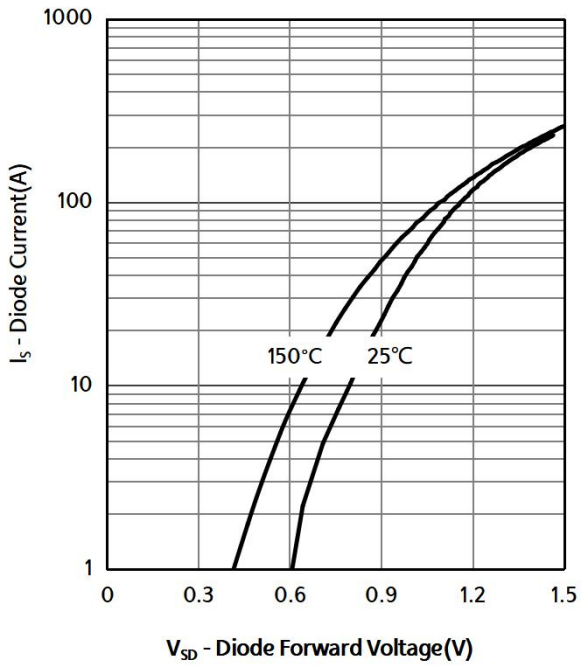
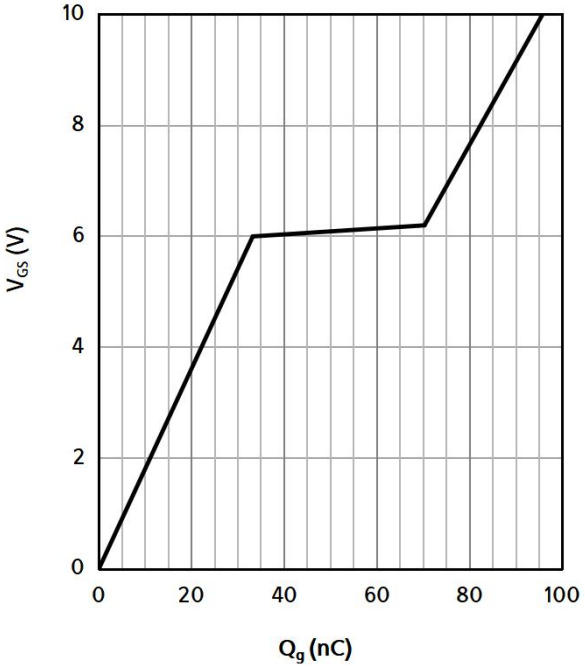
Fig 9: Body-diode Forward Characteristics	Fig 10: Gate Charge Characteristics
	
I_F=f(V_{SD});parameter: T_j	V_{GS}=f(Q_g); V_{DD}=480V; I_D=25A

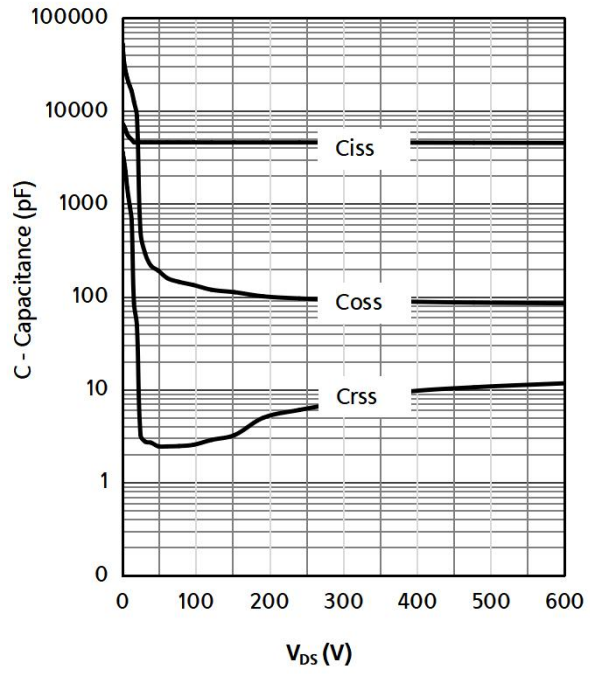
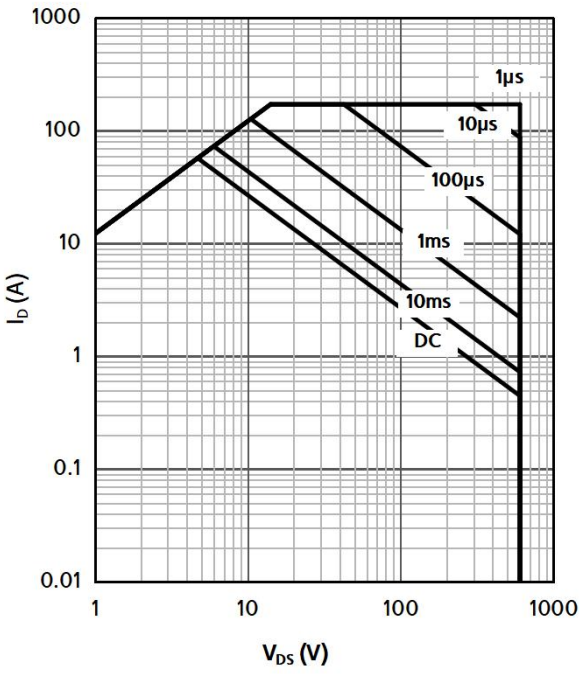
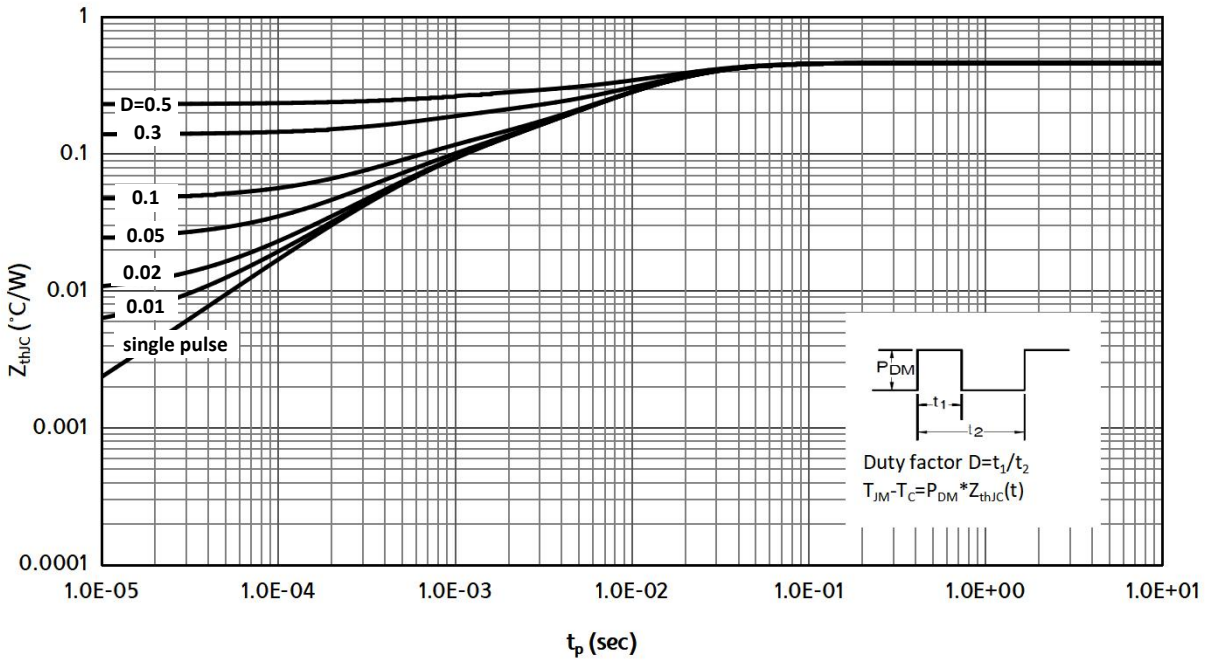
Fig 11: Capacitance Characteristics	Fig 12: Safe Operating Area
	
C=f(V_{DS}); V_{GS}=0V; f=100kHZ	I_D=f(V_{DS}); T_C=25°C;D=0;parameter: t_p

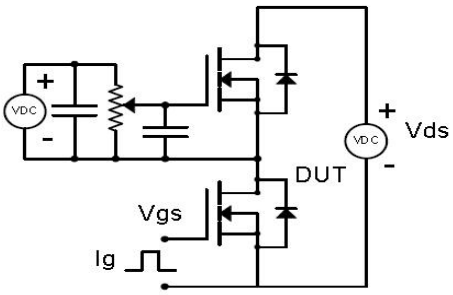
Fig 13: Max. Transient Thermal Impedance

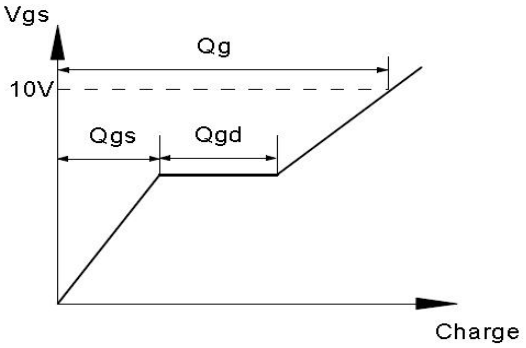


Z_{thJC}=f(t_p);parameter:D=t_1/t_2

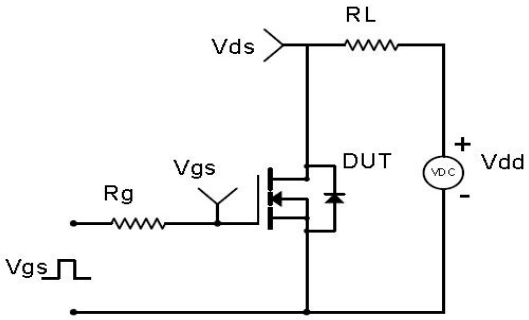
Test Circuit & Waveform

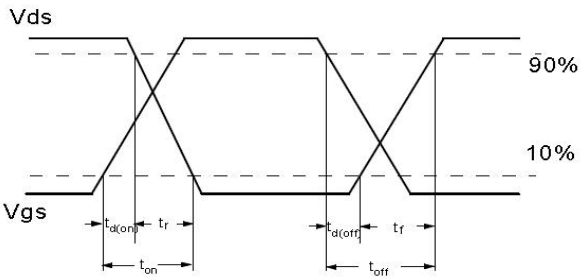
Gate Charge Test Circuit & Waveform



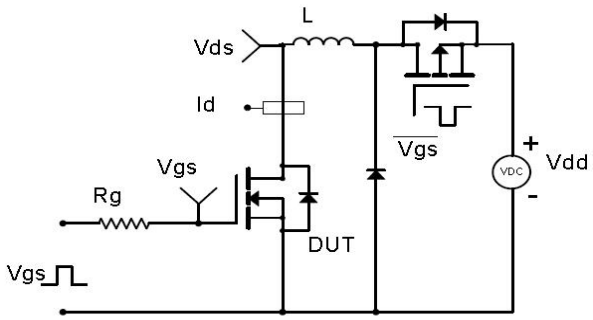


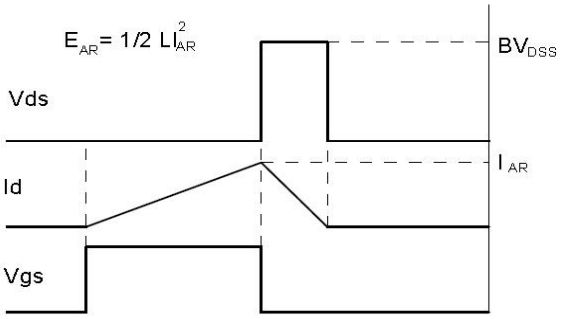
Resistive Switching Test Circuit & Waveforms



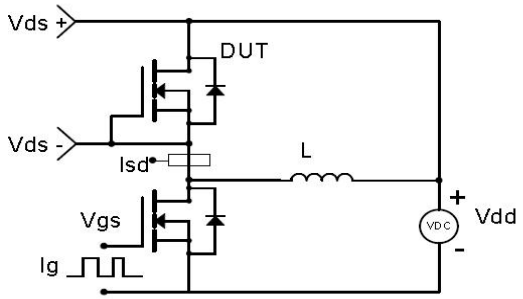


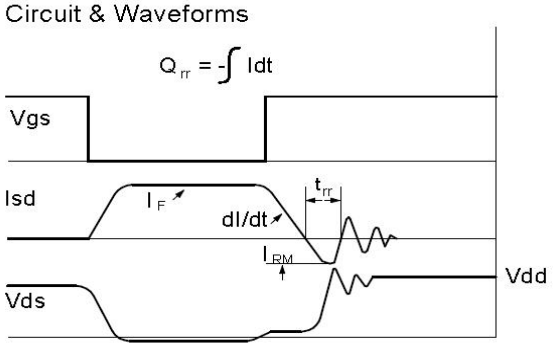
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



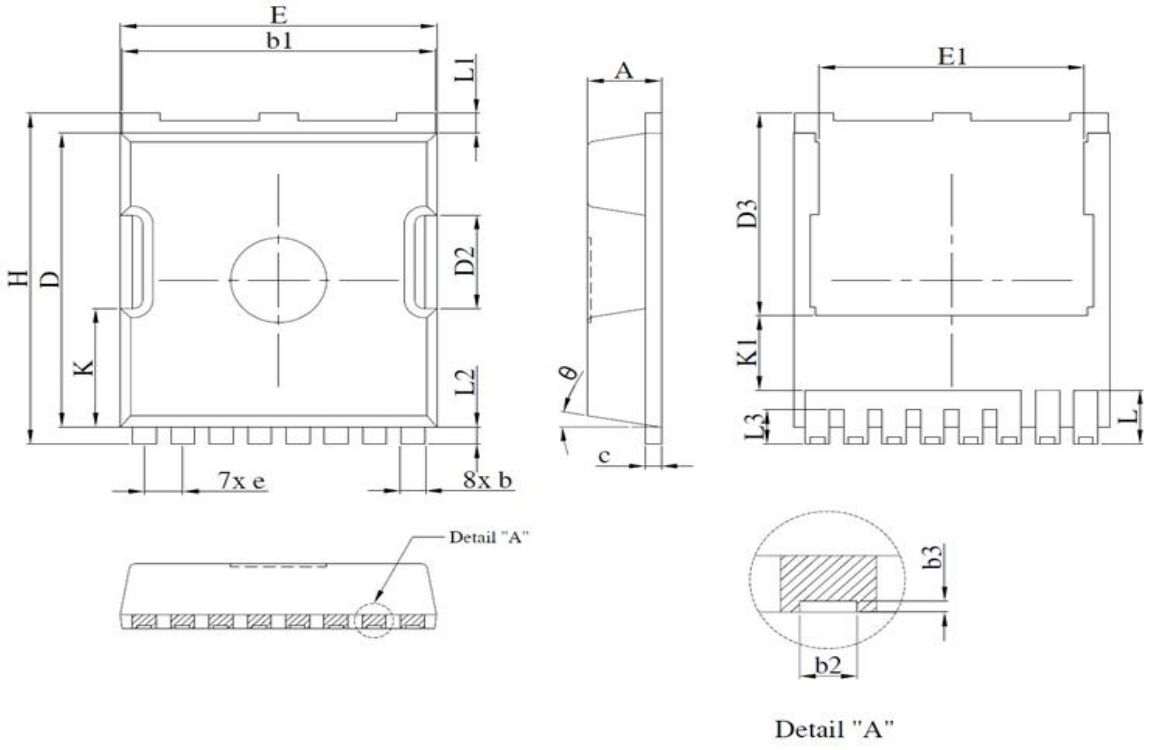


Diode Recovery Test Circuit & Waveforms





Package Outline: TOLL



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.15	2.45	0.085	0.096
b	0.65	0.90	0.026	0.035
b1	9.65	9.95	0.380	0.392
b2	0.45 REF		0.018 REF	
b3	0.10 REF		0.004 REF	
c	0.35	0.65	0.014	0.026
D	10.18	10.58	0.401	0.417
D2	3.15	3.45	0.124	0.136
D3	6.80	7.30	0.268	0.287
e	1.20 BSC		0.047 BSC	
E	9.70	10.10	0.382	0.398
E1	7.95	8.65	0.313	0.341
H	11.48	11.88	0.452	0.468
K	4.18 REF		0.165 REF	
K1	2.45	--	0.096	--
L	1.60	2.10	0.063	0.083
L1	0.50	0.90	0.020	0.035
L2	0.40	0.80	0.016	0.031
L3	1.00	1.30	0.039	0.051
θ	10° REF		10° REF	

Marking



NOTE:
NXBBAAAAY

N	—WB code (Usually omitted)
X	—Assembly location code
BB	—Fab code
AAAA	—Lot code
Y	—Bin code

Revision History

Revison	Major changes
2.0	Final version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qulified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semicondutor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.